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- Jack P.C. Kleijnen, Department of Information Management, Center for Economic Research, Tilburg University, The Netherlands
- Pedro Padro Herrero, Department of Enviromental Impact of Energy, Research Centre for Energy, Environment and Technology, Spain
- Stefano Tarantola, Institute for the Protection and Safety of the Citizen, European Joint Research Centre, Italy

FURTHER INFORMATION

The conference web site, www.samo2004.org, contains information about abstract submission, paper submission, conference registration, travel, maps, hotel and ski resorts. For other inquiries, please contact:

François M. Hemez
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Los Alamos, New Mexico, 87545

LOCATION

The SAMO 2004 conference will be held at the Inn at Loretto, in the heart of historical Santa Fe, New Mexico, the "Land of Enchantment." Santa Fe is located 60 miles (100km) from the Albuquerque International Airport, and may be reached by shuttle bus or automobile.

ACCOMODATIONS

A block of 100 rooms is available at the Inn at Loretto. The special conference rate is USD 99 per night for single occupancy, excluding taxes and hotel fees; USD 119 for double occupancy. Attendees are responsible for making their own reservations with the Inn at Loretto before February 5, 2004 to get the special conference rate.

The Inn at Loretto 211 Old Santa Fe Trail Santa Fe, New Mexico 87501 Phone: (+1)505-988-5531

Toll free: I-800-727-553 I (US only)

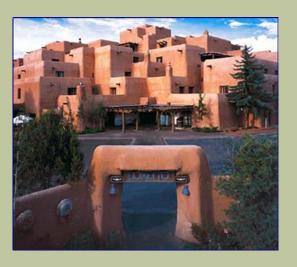
Web: www.hotelloretto.com



SAMO 2004

Fourth International Conference on

SENSITIVITY ANALYSIS OF MODEL OUTPUT



March 8 - 11, 2004

Santa Fe, New Mexico U.S.A.

Sponsored by

Los Alamos National Laboratory

Joint Research Centre of the European Commission

American Statistical Association

Society for Industrial and Applied Mathematics

www.samo2004.org

ABOUT SAMO 2004







HISTORY

The first international symposium on Sensitivity Analysis of Model Output (SAMO 95) was held in Italy, under the auspices of the Joint Research Centre (IRC) of the European Commission. It was organized by Andrea Saltelli of the Environment Institute of the IRC. Saltelli brought together a small, informal group of researchers dedicated to the advancement of methodologies for understanding uncertainty in mathematical simulations (models) of physical systems. The group put on SAMO 98 (Italy), while the Spains' Research Centre for Energy, Environment and Technology and two universities in Madrid arranged SAMO 2001 (Spain). Now, the SAMO tradition is reaching across the Atlantic ocean with SAMO 2004, to be held in the United States of America.

CONFERENCE SCOPE

The scope of the conference includes both sensitivity analysis—the study of the variation in the output of a model due to variation in model inputs (including factors related to numerical solution methods)—and also the quantification of the total uncertainty in model prediction arising from uncertainty in model inputs, as well as model structure. Methods to quantify input uncertainties lie within the scope. Topical areas of interest (with application in economics, engineering, environment, nuclear safety, and physics) include sensitivity and importance analysis, model calibration, model validation, decision-making under uncertainty, and methods to quantify model prediction error.

CONFERENCE FORMAT

The SAMO 2004 conference will promote indepth technical discussion by being a single-track meeting (no parallel sessions). The technical program will feature oral and poster presentations, and 9 invited lectures. Attendance will be limited to 100. In the spirit of past SAMO events, plenty of time will be available to encourage informal discussion.

REGISTRATION

The conference registration fee is USD 400 if received before January 5, 2004, and USD 480 after. The following are included in the registration fee: one CD-ROM set of the proceedings; four continental breakfasts; the Sunday night social; the conference banquet; and refreshments and snacks during the breaks and poster sessions.

To register, go to the SAMO 2004 web site at www.samo2004.org or contact François M. Hemez at Los Alamos National Laboratory (address provided on the other side).

ABSTRACTS

An abstract of about 1.000 words should be sent in MS/Word or PDF formats to hemez@lanl.gov. Please include the corresponding author's affiliation, complete mailing address, phone, fax and email. Because only 60 papers will be selected, preference will be given to work in which method development is supported by applications.

IMPORTANT DEADLINES

- Final abstract submission: September 15, 2003
- Notification of acceptance: October 15, 2003
- Final paper submission: December 31, 2003
- Conference registration: January 5, 2004
- Hotel reservation: February 5, 2004

PUBLICATION OF PAPERS

A special issue of Reliability Engineering and System Safety will publish peer-reviewed papers from the conference. Participants are invited to submit a full paper for consideration by May 20, 2004.

KEYNOTE SPEAKERS

- Katherine Campbell, Statistical Sciences, Los Alamos National Laboratory, U.S.A.
- Roger Cooke, Department of Mathematics, Delft University of Technology, The Netherlands
- Simon French, Manchester School of Business, University of Manchester, U.K.
- Jon Helton, Sandia National Laboratories, U.S.A.
- Michael McKay, Statistical Sciences, Los Alamos National Laboratory, U.S.A.
- Max Morris, Department of Statistics, Iowa State University, U.S.A.
- Anthony O'Hagan, Department of Probability and Statistics, University of Sheffield, U.K.
- Andrea Saltelli, Institute for the Protection and Safety of the Citizen, European Joint Research Center, Italy
- Timothy Trucano, Sandia National Laboratories, U.S.A.